Search Notes

| Application/Control No. | No. Applicant(s)/Patent under Reexamination |
|-------------------------|---|
| 09/766,558              | MOTIWALA ET AL.                             |

09/766,558

Examiner Ted M. Wang Art Unit 2611

**SEARCHED** Subclass Examiner Class Date

| 375 | 140, 326 | 12/21/2007 | TW |
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| 375 | 142, 143 | 12/21/2007 | TW |
| 375 | 150, 152 | 12/21/2007 | TW |
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| INTERFERENCE SEARCHED |          |            |          |  |
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| Class                 | Subclass | Date       | Examiner |  |
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| SEARCH NOT<br>(INCLUDING SEARCH  |            | )     |
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|  | DATE       | EXMR  |
| EAST - USPGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB, see attached search report   | 12/21/2007 | τw    |
| ODP - searched and reviewed  | 12/21/2007 | TW    |
| Inventor search - ((Quaeed with<br>Motiwala) or (Christopher with Riddle)<br>or (Luca with Blessent) or ("Shih-Yi"<br>with Yeh) or (Ro | 12/21/2007 | T.W   |
| IEEE advance search - (partition* or division or divid* or separat* or pars* or break* or broke*) an frame and portion                 | 12/21/2007 | TW    |
| IEEE author's search - Motiwala Q. or<br>Riddle C. or Blessent L. or Yeh S. Y.   | 12/21/2007 | TW    |
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